

**Supporting Information for**

**Asymmetric Fused Thiophenes for Field-Effect Transistors:  
Crystal Structure-Film Microstructure-Transistor  
Performance Correlations**

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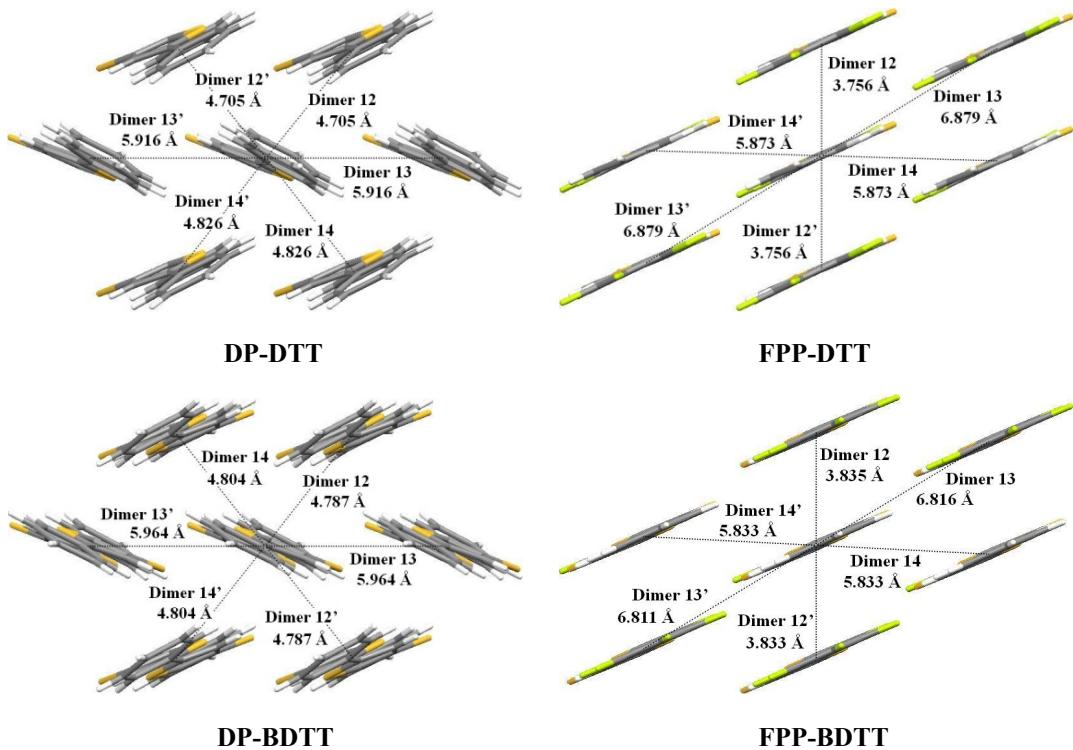
Keywords : Dithienothiophene (DTT), organic thin-film transistor (OTFT), thin film structure, single crystal, self-assembled monolayer (SAM)

**Table S1.** Summary of Crystal Structure Data for compounds **1-4**.<sup>a</sup>

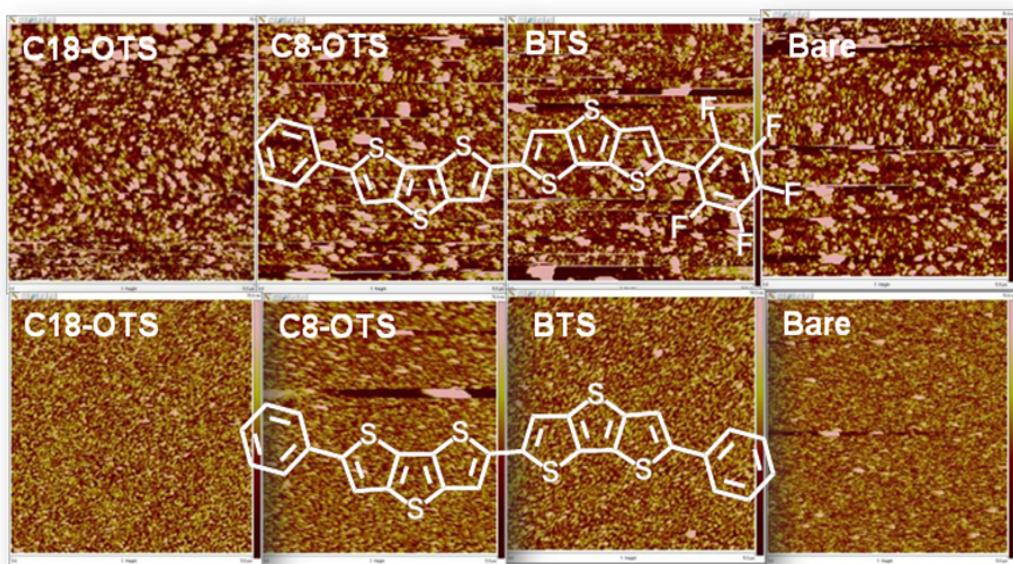
Compound	<b>1</b>	<b>2</b>	<b>3</b>	<b>4</b>
Empirical formula	C20H7F5S3	C20H12S3	C28H9F5S6	C28H14S6
Formula weight	438.44	348.48	632.71	542.75
Temperature (K) <sup>b</sup>	100(2)	200(2)	296(2)	296(2)
Crystal system	Monoclinic	Monoclinic	Triclinic	Monoclinic
Space group	<i>P</i> 21/c	<i>P</i> 21/c	P-1	P2(1)/c
Unit cell dimensions (Å)	$a = 5.8734(2)$ $\alpha = 90^\circ$	$a = 7.468(4)$ $\alpha = 90^\circ$	$a = 3.8338(5)$ $\alpha = 86.15(1)^\circ$	$a = 5.9639(18)$ $\alpha = 90^\circ$
	$b = 36.1226(12)$ $\beta = 91.677(2)^\circ$	$b = 5.916(3)$ $\beta = 94.01(4)^\circ$	$b = 5.8334(8)$ $\beta = 87.92(1)^\circ$	$b = 7.509(2)$ $\beta = 92.83(1)^\circ$
	$c = 7.4967(2)$ $\gamma = 90^\circ$	$c = 34.719(15)$ $\gamma = 90^\circ$	$c = 26.039(4)$ $\gamma = 87.04(1)^\circ$	$c = 50.362(15)$ $\gamma = 90^\circ$
<i>V</i> , Å <sup>3</sup>	1589.85(9)	1530.15(449)	579.93(49)	2252.61(137)
<i>Z</i>	4	4	1	4
<i>d</i> (calc), g/cm <sup>3</sup>	1.832	1.5126	1.81154	1.60028
Absorption coefficient (mm <sup>-1</sup> )	0.525	0.479	0.651	0.626
F(000)	880	720	318	1112
R <sub>All</sub>	0.1794	0.2708	0.1096	0.2014
Crystal size (mm)	0.44 × 0.20 × 0.04	0.60 × 0.46 × 0.01	0.33 × 0.14 × 0.01	0.28 × 0.19 × 0.01
Reflections collected	30972	8859	4776	12233
Independent reflections	3658	2642	2031	3592
R <sub>int</sub>	0.0554	0.1837	0.0598	0.1507
Final R indices [I>2sigma(I)] <sup>c</sup>	R1 = 0.0648 wR2 = 0.17	R1 = 0.1599 wR2 = 0.3548	R1 = 0.0692 wR2 = 0.1767	R1 = 0.0698 wR2 = 0.1613
R indices (all data)	R1 = 0.0706 wR2 = 0.1789	R1 = 0.2708 wR2 = 0.4062	R1 = 0.1096 wR2 = 0.2001	R1 = 0.2014 wR2 = 0.2479

<sup>a</sup> CCD area detector diffractometer; Mo K $\alpha$  radiation;  $\lambda = 0.71073$  Å. <sup>b</sup> Temperature for data collection. <sup>c</sup> Refinement method: Full-matrix least-squares on F2.

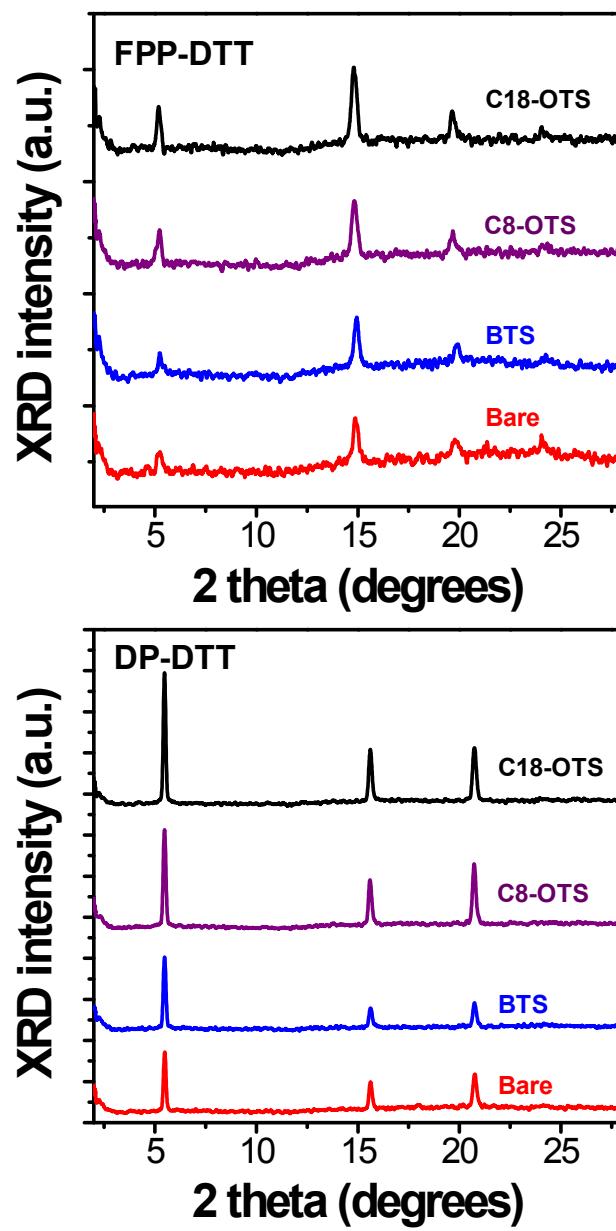
**Table S2.** Centroid-to-centroid distance ( $L$ ) in the crystal structures, calculated reorganization energies ( $\lambda^+$ ), electronic couplings ( $t^+$ ), and mobilities ( $\mu^+$ ) for hole transport.



Compound	Pair	$L$ (Å)	$\lambda^+$ (eV)	$t^+$ (eV)	$\mu^+$ ( $\text{cm}^2 \text{V}^{-1} \text{s}^{-1}$ )
<b>FPP-DTT(1)</b>	Dimer12	3.76	0.258	0.178	2.35
	Dimer13	6.88		0.000	0.00
	Dimer14	5.87		0.006	0.01
<b>DP-DTT (2)</b>	Dimer12	4.71	0.247	0.026	0.09
	Dimer13	5.92		0.001	0.00
	Dimer14	4.83		0.023	0.07
<b>FPP-BDTT(3)</b>	Dimer12	3.84	0.239	0.140	1.89
	Dimer12'	3.83		0.153	2.26
	Dimer13	6.82		0.000	0.00
	Dimer14	5.83		0.004	0.00
<b>DP-BDTT(4)</b>	Dimer12	4.79	0.237	0.025	0.10
	Dimer13	5.96		0.000	0.00
	Dimer14	4.80		0.025	0.10



**Figure S1.** AFM images ( $5 \times 5 \mu\text{m}^2$ ) of films (50 nm) of **FPP-BDTT (3)** and **DP-BDTT (4)** on various substrates.



**Figure S2.** X-ray Diffraction pattern of thin films of **FPP-DTT** (**1**) and **DP-DTT** (**2**) on various substrates.